# Crystal Structure of $\mathbf{M n}_{3} \mathbf{S i}_{\mathbf{2}} \mathbf{T e}_{\mathbf{6}}$ 

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#### Abstract

The synthesis, magnetic, and electrical properties of a new silicon manganese telluride, semiconducting and ferrimagnetic, has been previously reported. The X-ray determination of the crystal structure of this compound was achieved by means of direct methods and three-dimensional Fourier syntheses. The final least-squares $R_{w}$ factor of the refinement is $R_{w}=0.035$. According to this study the chemical formula is $\mathrm{Mn}_{3} \mathrm{Si}_{2} \mathrm{Te}_{6}$ with $Z-2$, the trigonal unit cell is $a=7.029(2), c=14.255(3) \AA$, the space group is $P \overline{3} 1 c$. The crystal structure can be described as one of a layer-type compound. Along the $c$-axis direction, we observe a fully occupied layer of Mn or Si pairs octahedra, then a partially occupied layer of ordered Mn octahedra, and so on. The surroundings of Si atoms are similar to the one found in $\mathrm{Si}_{2} \mathrm{Te}_{3}$, and the fully occupied layer of octahedra may be compared to the one found in $\mathrm{Fe}_{2} \mathrm{P}_{2} \mathrm{Se}_{6}$. (c) 1986 Academic Press, Inc.


## Introduction

In the manganese telluride family, only the binary compounds MnTe and $\mathrm{MnTe}_{2}$ have been extensively studied. Both compounds are antiferromagnetic. Very few ternary Mn tellurides have been studied up to now ( 1,2 ). The series $\mathrm{Mn}_{2} \mathrm{Te}_{4}$ with $A=$ $\mathrm{Al}, \mathrm{Ga}$, In have been synthesized; these compounds, with a tetragonal crystal structure, are paramagnetic down to $1.3 \mathrm{~K}(3,5)$.
In an attempt to prepared a high-temperature phase of $\mathrm{MnAl}_{2} \mathrm{Te}_{4}$ in a silica cell, a new compound has been obtained. This compound was found to be hexagonal, semiconducting, and ferrimagnetic below $82 \mathrm{~K}(6)$. The chemical formula was found
by microprobe analysis to be close to $\mathrm{Mn}_{1.3} \mathrm{SiTe}_{3}$. We decided to prepare single crystals and to determine their structure.

## Crystal Growth

Single crystals have been grown by the vapor phase transport technique from a mixture of the elements with a slight excess of tellurium and with iodine as the transport agent; the thermal gradient was from 800 to $720^{\circ} \mathrm{C}$. Complete reaction was not achieved after 8 days; in the cooler zone, we found thin, roughly hexagonal, shiny dark platelets with typical dimensions $2 \times 2 \times$ 0.1 mm .

TABLE I
Positional and Thermal Parameters ( $U_{i j}$ in $\AA^{2} \times 10^{4}$ )

| Atom | Position | $x$ | $y$ | $z$ | $U_{11}$ | $U_{22}$ | $U_{33}$ | $U_{12}$ | $U_{13}$ | $U_{23}$ | Occupation |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathbf{M n}(1)$ | $4 f$ | $\frac{1}{3}$ | 3 | $0.00068(8)$ | 158(6) | 158(6) | 242(7) | 079(3) | 0 | 0 | 1 |
| Mn(2) | 2 c | $\pm$ | $\frac{3}{3}$ | $\frac{1}{4}$ | 184(5) | 184(5) | 20066) | 092(3) | 0 | 0 | 0.966(3) |
| Si | $4{ }^{\text {e }}$ | 0 | 0 | 0.08153(13) | $096(7)$ | 096(7) | 168(9) | 048(4) | 0 | 0 | 1 |
| Te | 12i | 0.65869(3) | 0.00361(3) | 0.12788(2) | 122(1) | 125(1) | 188(2) | 068(1) | 030(1) | 024(1) | 1 |

## Crystal Structure Determination

According to precession photographs, the cell is hexagonal with parameters $a=$ 7.029(2) $\AA, c=14.255(3) \AA$. The $c$ axis is perpendicular to the platelet, and the $a$ axis is parallel to the edges. The $h h l$ reflections with $l=2 n+1$ are absent; the possible space groups are $P 6_{3} m c, P \overline{6} 2 c, P 6_{3} / m m c$ or $P 3_{1} c, P \overline{3}_{1} c$, if the true symmetry is trigonal.

A triangular prismatic crystal of 0.016 cm width and 0.012 cm thickness was set on a four-circle diffractometer. The intensities of a total of 4503 reflections were collected in the $\omega$-scanning mode, using $\mathrm{Ag} K \alpha$ radiation up to a $25^{\circ}$ Bragg angle in half the Ewald sphere. An absorption correction was performed, considering a sphere of equivalent volume ( $\mu R=0.6$ ).

Investigation of equivalent reflections shows that the true symmetry is trigonal and averaging in the $\overline{3} 1 \mathrm{~m}$ Laue class lead to 832 independent reflections. Wilson statistic giving a centric distribution of the $E$ normalized structure factors, we applied the direct methods in $P \overline{3} 1 c$ space group. Because of the absence of the $h k 2 n+1$ reflections among the 200 larger $E$ 's, the origin couldn't be fixed. Nevertheless, the absence of this reflection class shows that the two halves of the unit cell are almost identical in the $c$ axis direction. Direct methods and Fourier synthesis were then performed in the $P \overline{3} 1 m$ space group corresponding to the $a, b, c / 2$ unit cell, after reindexing of the reflections. The $\mathrm{Te}, \mathrm{Mn}$, and Si atoms could be located, respectively, in
the $6 k, 2 c, 2 e$ positions of the $P \overline{3} 1 m$ space group.

Returning to the true unit cell, a Fourier difference synthesis showed the presence of one more Mn atom in the 2 c position of the $P \overline{3} 1 c$ space group. Including the Te , $\mathrm{Mn}, \mathrm{Si}$ atoms previously located in the $12 i$, $4 f$, and $4 e$ positions of $P 31 c$, the true chemical formula is $\mathrm{Mn}_{3} \mathrm{Si}_{2} \mathrm{Te}_{6}$ with $Z=2$. Using reflections with $F>2 \sigma$ and allowing the anisotropic temperature factors and site populations to vary, a least-squares refinement gave the parameters listed in Table I. The $R(F)$ and $R_{w}(F)$ factors are, respectively, 0.0412 and 0.035 . The weighting scheme used is $w(F)=1 / \sigma(F)^{2}$ with $\sigma(F)$ $=1 / 2\left(\left(\sigma(I)+(0.02 I)^{2}\right) / I\right)^{1 / 2}$ where $\sigma(I)$ is the standard deviation of the observed intensity $I$.

## Structure Description

Along the $c$-axis layers of the Te atoms conform to hexagonal close packing, with each layer of Te atoms being of distance $c / 4$ from the following one. The Mn atoms or pairs of Si atoms are situated in octahedral sites.

Octahedra containing $\mathrm{Mn}(1)$ atoms $(z \approx$ 0 , or $z \approx \frac{1}{2}$ ) are surrounded by 3 octahedra containing Mn atoms and with 3 octahedra containing pairs of Si atoms. Each Si pair octahedron is surrounded by 6 Mn octahedra (Fig. 1). Mn(2) octahedra ( $z \approx \frac{1}{4}$ or $\frac{3}{4}$ ) are surrounded by 6 empty octrahedra (Fig. 2). Along the $c$ axis the following sequence


Fig. 1. Fully occupied layer of $\mathrm{Mn}(1)$ or Si pairs octahedra.


Fig. 2. Partially occupied layer of $\mathrm{Mn}(2)$ octahedra.


Fig. 3. Sequence of fully and partially occupied layers along the $c$ axis.

TABLE II
Bond Distances in $\mathrm{Mn}_{3} \mathrm{Si}_{2} \mathrm{Te}_{6}$

may be observed: a fully occupied layer of $\mathrm{Mn}(1)$ or Si pairs octahedra, then a partially occupied layer of $\mathrm{Mn}(2)$ octahedra, again a fully occupied layer of $\mathrm{Mn}(1)$ or Si pairs octrahedra followed by a partially occupied layer of $\mathrm{Mn}(2)$ octahedra and so on.

A fully occupied layer octahedron shares one edge with six octahedra of the same layer. A partially occupied layer octahedron shares one face with the ones of the upper or lower layer (Fig. 3).

## Discussion

The arrangement of the Si atoms may be compared to the one found in $\mathrm{Si}_{2} \mathrm{Te}_{3}$ (7). In
this compound octahedra containing two Si atoms are observed. $\mathrm{Si}-\mathrm{Si}$ bond lengths ( 2.269 to $2.345 \AA$ ), $\mathrm{Si}-\mathrm{Te}$ bond lengths ( 2.451 to $2.662 \AA$ ), and $\mathrm{Te}-\mathrm{Si}-\mathrm{Te}$ angles ( $113.50^{\circ}$ to $116.85^{\circ}$ ) (7) are comparable with those in Table II. $\mathrm{Si}_{2}$ pairs with comparable interatomic distances are also observed in $\mathrm{Na}_{6} \mathrm{Si}_{2} \mathrm{Te}_{6}$ and in $\mathrm{K}_{6} \mathrm{Si}_{2} \mathrm{Te}_{6}$ (8). The fully occupied layer arrangement is similar to the one found in $\mathrm{Fe}_{2} \mathrm{P}_{2} \mathrm{Se}_{6}$ (9). In this selenide, we observe octahedra containing $P_{2}$ units. Each $P_{2}$ octahedron is surrounded by 6 Fe octahedra, and each Fe octahedron is surrounded by 3 octahedra containing Fe atoms and 3 octahedra containing pairs of $P$ atoms, as in $\mathrm{Mn}_{3} \mathrm{Si}_{2} \mathrm{Te}_{6}$.

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